

# Mj Deen

## List of Publications by Year in descending order

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16  
papers

1,112  
citations

759233

12  
h-index

1125743

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16  
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16  
docs citations

16  
times ranked

640  
citing authors

#	ARTICLE	IF	CITATIONS
1	Towards an optimal MIIM diode for rectennas at 10.6 $\hat{\wedge}$ 1/4m. Results in Materials, 2021, 11, 100204.	1.8	9
2	Towards low-cost, high-sensitivity, integrated biosensors. , 2008, , .		1
3	A 4-mW monolithic CMOS LNA at 5.7GHz with the gate resistance used for input matching. IEEE Microwave and Wireless Components Letters, 2006, 16, 188-190.	3.2	43
4	A review of gate tunneling current in MOS devices. Microelectronics Reliability, 2006, 46, 1939-1956.	1.7	150
5	High-Frequency Noise of Modern MOSFETs: Compact Modeling and Measurement Issues. IEEE Transactions on Electron Devices, 2006, 53, 2062-2081.	3.0	104
6	Compact-Modeling Solutions For Nanoscale Double-Gate and Gate-All-Around MOSFETs. IEEE Transactions on Electron Devices, 2006, 53, 2128-2142.	3.0	91
7	MOSFET Modeling for RF IC Design. IEEE Transactions on Electron Devices, 2005, 52, 1286-1303.	3.0	128
8	A New Method for the Channel-Length Extraction in MOSFETs With Sub-2-nm Gate Oxide. IEEE Electron Device Letters, 2004, 25, 202-204.	3.9	12
9	Effects of hot-carrier stress on the performance of the lc-tank cmos oscillators. IEEE Transactions on Electron Devices, 2003, 50, 1334-1339.	3.0	48
10	High-frequency small signal AC and noise modeling of MOSFETs for RF IC design. IEEE Transactions on Electron Devices, 2002, 49, 400-408.	3.0	68
11	Channel noise modeling of deep submicron MOSFETs. IEEE Transactions on Electron Devices, 2002, 49, 1484-1487.	3.0	133
12	A general noise and S-parameter deembedding procedure for on-wafer high-frequency noise measurements of MOSFETs. IEEE Transactions on Microwave Theory and Techniques, 2001, 49, 1004-1005.	4.6	105
13	Extraction of the induced gate noise, channel noise, and their correlation in submicron MOSFETs from RF noise measurements. IEEE Transactions on Electron Devices, 2001, 48, 2884-2892.	3.0	99
14	High frequency noise of MOSFETs I Modeling. Solid-State Electronics, 1998, 42, 2069-2081.	1.4	99
15	MOSFET modeling for low noise, RF circuit design. , 0, , .		21
16	Analytical modeling of MOSFET noise parameters for analog and RF applications. , 0, , .		1